XRD of sonochemically synthesized ZnO nanoparticles

XRD revealed the regular XRD pattern. The peaks at 2*θ* = 31.772°, 34.420°, 36.256°, 56.602°, and 62.858°, are assigned to the (100), (002), (101), (110), and (103) reflection lines, respectively (PDF: 089-0510) for hexagonal ZnO wurtzite. No diffraction lines associated with impurities were detected.

